

2/7/1 (Item 1 from file: 351)

DIALOG(R)File 351:Derwent WPI

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System for measuring skin condition

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Number of Countries: 001 Number of Patents: 001

Patent Family:

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KR 2002022265	A	20020327	KR 200054970	A	20000919	200265 B

Priority Applications (No Type Date): KR 200054970 A 20000919

Patent Details:

Patent No	Kind	Lan Pg	Main IPC	Filing Notes
KR 2002022265	A	1	A61B-010/00	

Abstract (Basic): KR 2002022265 A

NOVELTY - Provided is a system for measuring skin conditions which makes it possible to exactly examine and determine the skin conditions of an individual, and thereby consumers to select a cosmetic product suitable for their skin conditions.

DETAILED DESCRIPTION - The system comprises an output device(6) having a monitor(6a) and a printer(6b), a personal computer(5) having an image board(5a) inside and a video microscope(1) connected to a lighting apparatus(1a) for observing corneous cells. The system has a device for measuring sizes of the skin pores, in which a photograph taken by the video microscope is compared to a reference image of the skin pores stored in the computer and the result is output through the output device(6). Also, the system has a device for measuring the peeling levels of the stratum corneous, in which a photograph taken by the video microscope is compared to a reference image of the stratum corneous stored in the computer and the result is output through the output device(6). In addition, the system has devices for measuring the color(2) and the oil(3) and moisture(4) level of the skin, in which the respective measured values are compared to reference values stored in the computer and the results are output through the output device(6).

pp: 1 DwgNo 1/10

Derwent Class: P31

International Patent Class (Main): A61B-010/00

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SYSTEM FOR MEASURING SKIN CONDITION

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Applicant(s): IDIPS LAB CO LTD (KR)

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EC Classification:

Equivalents:

Abstract

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